Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/517,040	WEISS ET AL.	
Examiner	Art Unit	
CUONG H. NGUYEN	3661	

SEARCHED				
Class	Subclass	Date	Examiner	
701	2,24			
		,		

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
DERWENT			
IEEE Xplore			
Inventors'names search			